

RELIABILITY MONITOR

CORRECTIVE ACTION SUMMARY

JOB NO.	PRODUCT	MONITOR DATE	STRESS/TEST	FAILURE MODE	FA#	FAILURE MECHANISM	CORRECTIVE ACTION
P-16943	DS1000	Feb-96	I/L	1-Icc	96-0040	In Process	
P-15358	DS1230Y	Mar-95	THB 959 Hr	1-Data Retention	95-0104	In Process	
P-16107	DS1230Y	Jul-95	T/C 1000~	2-Batt. level high	Engr Eval	In Process	
P-16351	DS1230AB	Sep-95	Storage Life	1-StackB Tru	95-0226	In Process	
P-16443	DS1233	Aug-95	A/C	1-Continuity	95-0198	Bond pad corrosion	?
P-16662	DS1233	Oct-95	A/C	1-Continuity	96-0021	In Process	
P-16698	DS1267	Oct-95	A/C	1-Output Current	96-0026	In Process	
P-16486	DS12885	Oct-95	I/L	2-Functional	95-0223	In Process	
P-16605	DS12885	Nov-95	P/C	1-Icc	95-0241	In Process	
P-16785	DS12885	Dec-96	HV/L 336 Hr	1-Continuity	96-0012	Electrical Overstress	n/a
P-16813	DS12885	Jan-96	I/L	1-Bat1 Lkg	96-0011	In Process	
P-15969	DS12887	Jun-95	THB 274	1-Didn't wake up	Engr Eval	In Process	
P-15969	DS12887	Jun-95	THB 959	2-Didn't wake up	Engr Eval	In Process	
P-16277	DS12887	Aug-95	THB 959	1-Didn't wake up	Engr Eval	In Process	
P-12370	DS1585	May-94	HV/L 336 Hr	1-Inleak Lo	94-0152	In Process	
P-15955	DS1643	Jun-95	M/S 960 Hr	1-Ilkg Hi	95-0238	In Process	
P-15955	DS1643	Jun-95	M/S 960 Hr	1-Freshness Seal	95-0238	In Process	
P-16247	DS1643	Aug-95	M/S 960 Hr	2-Time Reading	95-0239	In Process	
P-16653	DS1643	Nov-95	T/C 1000~	1-Time Reading	96-0020	In Process	
P-16654	DS1643	Nov-95	M/S 960 Hr	4-Ikg Lo	Engr Eval	In Process	
P-16748	DS1992	Dec-95	0 Hr	14-Vbatt. Low	Engr Eval	In Process	
P-16515	DS2107A	Oct-95	A/C	1-Term R8	95-0216	Top passivation delamination	?
P-14504	DS21S07	Dec-94	THB 274 Hr	1-IIH R1-R10	95-0084	In Process	
P-16113	DS21S07	Jul-95	THB 274 Hr	2-Vref @ 4V	95-0157	Low process Vt	?
P-14089	DS2165	Nov-94	HV/L 1000 Hr	1-Opens A4	95-0064	In Process	

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P-14089	DS2165	Nov-94	HV/L 1000 Hr	1-Romdump	95-0064	In Process	
P-16824	DS2165	Jan-96	I/L	1-Shorts Xout	Engr Eval	Electrical Overstress	n/a
P-16747	DS2250	Dec-95	M/S 192	1-Branch	Engr Eval	Device passed retest	n/a
P-16470	DS2401	Dec-95	I/L	3-DQ Resistance	96-0029	In Process	
P-16657	DS2434	Nov-95	THB 100 Hr	1-icc	96-0052	In Process	
P-16958	DS2434	Feb-96	I/L	1-icc	96-0054	In Process	
P-14097	DS2502	Nov-94	I/L	1-Read Matrix	95-0041	In Process	
P-16379	DS2502	Sep-95	I/L	1-Read Matrix	95-0197	?	
P-16379	DS2502	Sep-95	I/L	1-Iol/Vol	95-0197	?	
P-16894	DS2502	Dec-95	HV/L 1000 Hr	1-Read Matrix	Engr Eval	In Process	
P-16896	DS2502	Dec-95	THB 959 Hr	1-DQ Resistance	Engr Eval	In Process	
P-17086	DS2502	Mar-96	P/C	1-Preset Matrix	Engr Eval	In Process	
P-17098	DS2502	Mar-96	P/C	1-DQ Resistance	Engr Eval	In Process	
P-13963	DS5002	Oct-94	HV/L 1000 Hr	2-Trip & State	95-0087	In Process	
P-16833	DS5002	Jan-96	Ultrasound	2-Delamination	Engr Eval	No related failures after Rel. stress	n/a
P-16864	DS5002	Jan-96	HV/L 1000 Hr	1-Battest	Engr Eval	In Process	
P-15567	DS80C320	Jan-95	T/C 300~	2-Continuity	95-0125	In Process	
P-16996	DS80C320	Feb-96	THB 100 Hr	1-Iccsp_in	96-0051	In Process	

0 Hr	Zero Hour Test	T/C	Temperature Cycle
P/C	Preconditioning	THB	Temperature Humidity Bias
I/L	Burn-in 48 Hr	A/C	Autoclave
HV/L	Burn-in (7.0 V)	Ultrasound	"
M/S	Moisture Soak	Solder	Solderability
S/L	Storage Life		